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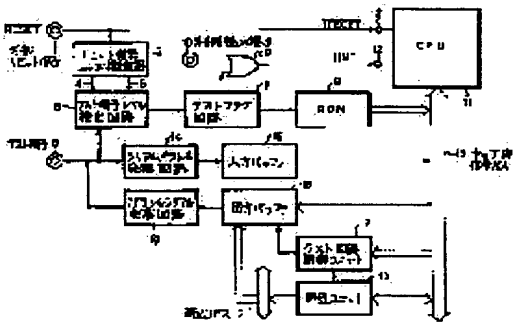
(54) SEMICONDUCTOR INTEGRATED CIRCUIT

(57)Abstract:
PURPOSE: To simplify a hardware and a software, to shorten a testing time and to improve an accuracy of a test by setting a test circuit of a semiconductor integrated circuit and sampling data with one test terminal.
CONSTITUTION: A test flag circuit 7 is set by inputting a test terminal 8 at the time of falling of an external reset signal [external 1], and thus a CPU 11 starts a test circuit control unit 17 of a peripheral unit 13 on a chip by a ROM 9 which writes a test circuit starting procedure program. Setting of a condition at the time of testing and collection of data are conducted by a serial communication from the terminal 8 by using a serial/parallel converter 14 and a parallel/series converter 19.



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